Polarization-interference micromethod for the study of mutual diffusion in polymer systems

V.G. Chertkov and A.Ye. Chalykh*

Institute of Physical Chemistry, Academy of Sciences of the USSR, Leninsky Prospect, 31, SU-117915 Moscow, USSR

SUMMARY

A polarization-interference technique is developed for the study of mutual diffusion that is applicable to systems covering the whole concentration range from polymer \sim lowmolecular-weight compound systems to polymer - oligomer systems. The technique is based on variations of the refraction index within the diffusion zone and is shown to have advantages over similar ones. Its accuracy in terms of wavelength is 0.04 . The polybutadiene - dloctyl phtalate system is used to illustrate how the concentration distribution of the components is calculated.

INTRODUCT ION

Optical methods have now been established as a practical means for studying diffusion processes in polymer systems. They are based on measurements of either the refraction index n or its gradient drJdx within the diffusion zone. There are both interference (e.g. the multibeam interference and interference-polarization method by Tsvetkov (1,2)) and refractometry methods $(3,4)$.

The technique to be described was developed to study mutual diffusion processes in polymer systems. It makes use of a polarization-interference optical system, which can be used to measure the refraction index variation within the diffusion zone. Unlike other devices of the same kind the initially polarized light beam is separated into its ordinary and extraordinary components, which have a path difference between them, as soon as it has left the sample. The system yields the high locality and small dimensions characteristic of multibeam interferometers (I) and the sensitivity to variations in n that is characteristic of Tsvetkov's device (2). The technique at issue was not reported as practicable for diffusion measurements before.

^{*} To whom offprint requests should be sent

DESCRIPTION OF THE TECHNIQUE

The optical route of our microscope is shown in Fig.1. The main component is the polarization-interference unit. which consists of a Vollaston doubling prism, a polarizer, am analyzer, and a sllt diaphragm. The prism is to separate the initially polarized light beam that has passed through the sample into two polarized ones: ordinary and extraordinary beams, and to introduce a phase shift between them. The angular separation of these beams r increases with increasing refracting angle of the prism. The slit is adjusted so that it is parallel to the refracting face of the prism. Together with the condenser the slit forms a collimator; parallel beams of coherent light leave it to interfere in the visual field of the microscope.

The interference pattern is formed as follows. Let the sample under study have a diffusion zone within which the refraction index n changes from $n₁$, the index of the pure low molecular weight component to n_{0} , the index of the pure polymer. When the light beam polarized by the polarizer passes throughthe sample, it acquires a definite phase lag which varies within the diffusion zone. This wave reaches the objective and is separated into ordinary and extraordinary waves which are caused to diverge at some small angle, these waves

Fig.1 Optical route of a polarization-interference microscope:

1) camera 2) eyepiece
3) analyzer 4 Vollaston prism $\begin{array}{c} 5 \\ 5 \\ 6 \end{array}$ sample objective 7) condenser 8) slit diaphragm
9) slit 10) polarizer 11) mirror 12) field diaphragm 13 collector 14) light source

Fig.2 (a) Superposition of (1) an ordinary and (2) extra-
ordinary waves and (b) the calculation of the refraction
index variation within a diffusion zone.

Fig.3 Photograph
of the interference pattern in the pattern in the
polybutadiene (PB)
- dioctyl phtalate
(DOP) system at 20°C.
The diffusion time
is 16 min.

being polarized in perpendicular planes. No component of the waves other than that parallel to the direction of light vibration of the analyzer itself can be transmitted through it.

This means that after the waves have passed through the analyzer two waves are produced that are linearly polarized in parallel planes, Fig.2,a. These waves can interfere to form a pattern in the image plane of the microscope. The pattern will consist of straight interference bands if n~const outside the diffusion zone, and the pattern will be distorted inside the diffusion zone where n=const (Fig.3). To give rise to deviations in the interference bands in the diffusion zone it is necessary to adjust the initial boundary between the components at an angle α to the bands.

The refraction index variation within the diffusion zone is calculated by the following procedure. At first the distances between the beginning of the diffusion zone and several points within it are determined from

$$
x_i = x_i^* \sin \alpha, \quad i = 1, 2, 3, \dots \tag{1}
$$

and the corresponding difference between the refraction indexes of the ordinary and extraordinary waves

$$
\Delta n'_{i} = \frac{d'_{i} \lambda}{h!} \sin \alpha \qquad i = 1, 2, 3, \dots \tag{2}
$$

where λ is the wavelength of the light source; 1 is the thickness of the sample; h is the distance between the bands; x_i is the distance between the beginning of the diffusion zone and the i-th point on the photograph; d_i is the deviation of the band at this point. Having the relation $\Delta n_i^* = f(x_i)$ the refraction index profile is calculated (Fig.2,b): for any point x_1 satisfying the inequality $0 \le x_1 \le r'$ (where r' = $r \cos \alpha$ and r is the magnitude of shift between the two images) $\Delta n_{1} = \Delta n_{1}$ is defined. The value Δn_{2} is defined $\Delta n_{2} = \Delta n_{1} + \Delta n_{2}$ for the point $x_{2} = x_{1} + r_{0}$ Following this procedure the value of Δn_i for any point $x_i = x_1 + (i-1)r'$ is calculated from

$$
\Delta n_{i} = \sum_{k=1}^{i} \Delta n_{k}^{*}, \quad i = 1, 2, 3, ... \tag{3}
$$

We used a MPI-5 (Poland) microscope which gave an image separation ranging from 4 to 100 μ m, depending on the refracting angle of the prism and the objective used. The accu-

Fig.4 A scheme of a thermally regulated cuvette containing a diffusion cell:

- 1) thermally regu-
lated jacket
	- glass plates
- clamps
- spacers to determine capil-
- lary thickness
- 51 fastening screws sample

racy of measuring the path difference is λ /25.

This technique allows us to investigate the whole concentration range for polymer - low molecular weight compound systems and polymer - oligomer systems.

The technique is illustrated for the PB - DOP system at 20°C. The molecular mass of PB was 40 000, $M_{\odot} / M_{\gamma} = 1.13$, the refraction index of PB n_2^{20} = 1.5175 and that of DOP $n_1^{20} = 1.4852.$

' The polymer was placed between glass plates which form a flat capillary $100-200~\mu$ m thick. The plates were fixed into a cell and the cell placed into a thermally regulated cuvette (Fig.~). After making the temperature uniform the plasticizer was introduced into the capillary to produce an interference pattern, which was photographed at regular intervals (e.g., Fig.3). The data was processed according to equations (1 - 3) and the expression $c_2 = \Delta n/K$, where K is the increment of n. This results in a concentration profile of the polymer $c_2(x)$ in the diffusion zone. Figure 5 shows the results.

Fig.5 Concentration profiles in the **PB -** DOP system at 20"C: **1) @** rain \leq \leq \leq $\frac{1}{2}$ min) 16 min

The advantages of this technique over the method of optical wedge (q) ere its better accuracy (approximately one order of magnitude higher) and the elimination of the need to cover the internal surfaces of the plates with semi-transparent layers of metal or to form a wedge between the plates.

Thus this polarization- interference technique is a convenient and accurate method for studying mutual diffusion over wide concentration ranges and for a variety of systems. It is worth noting that the possibilities of this technique are far from being exhasted.

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